

### SSF80R850S-VB Datasheet

# N-Channel 800V (D-S) Super Junction Power MOSFET

PRODUCT SUMMA	RY		
V <sub>DS</sub> (V) at T <sub>J</sub> max.	800	)	
R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.85	
Q <sub>g</sub> max. (nC)	20		
Q <sub>gs</sub> (nC)	2.4		
Q <sub>gd</sub> (nC)	11		
Configuration	Single		

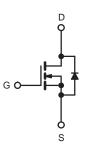
#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (C<sub>iss</sub>)
- · Reduced switching and conduction losses
- Ultra low gate charge (Qq)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial





N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)							
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			$V_{DS}$	800	V		
Gate-Source Voltage			$V_{GS}$	± 30	7 v		
Continuous Drain Current (T,I = 150 °C)	V <sub>GS</sub> at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$		7			
Continuous Drain Current (1) = 150 C)	VGS at 10 V	T <sub>C</sub> = 100 °C	Ι <sub>D</sub>	5.9	Α		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	11			
Linear Derating Factor				1.89/1.6/0.4	W/°C		
Single Pulse Avalanche Energy b			E <sub>AS</sub>	86	mJ		
Maximum Power Dissipation			$P_{D}$	99/97/46	W		
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		dV/dt	50	V/ns		
Reverse Diode dV/dt <sup>d</sup>			uv/ut	3.2	V/IIS		
Soldering Recommendations (Peak Temperature) c	for	10 s		300	°C		

- a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD}=50$  V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 3.5 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ ,  $dI/dt = 100 \text{ A/}\mu\text{s}$ , starting  $T_J = 25 \,^{\circ}\text{C}$ .



THERMAL RESISTANCE RATI	NGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	72	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.7	C/ VV

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static				•	,		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250  \mu\text{A}$		800	_	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		-	4	V
	_	V <sub>GS</sub> = ± 20 V		-	-	± 100	nA
Gate-Source Leakage	Source Leakage		$V_{GS} = \pm 30 \text{ V}$	-	-	± 1	μA
			= 800 V, V <sub>GS</sub> = 0 V	-	-	1	<del>                                     </del>
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 4 A	-	0.85	-	Ω
Forward Transconductance	9 <sub>fs</sub>		= 30 V, I <sub>D</sub> = 4 A	-	19	-	S
Dynamic					·		
Input Capacitance	C <sub>iss</sub>	V - 0V		-	373	_	pF
Output Capacitance	C <sub>oss</sub>	1	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$ f = 1  MHz		26	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	1			14	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	46	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	64	-	
Total Gate Charge	Qg			-	26		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$I_D = 4 A, V_{DS} = 520 V$	-	2.1	-	nC
Gate-Drain Charge	$Q_{gd}$	1		-	2.8	-	1
Turn-On Delay Time	t <sub>d(on)</sub>	1		-	26	-	ns
Rise Time	t <sub>r</sub>	Von	$V_{DD}$ = 520 V, $I_{D}$ = 4 A, $V_{GS}$ = 10 V, $R_{g}$ = 9.1 $\Omega$		55.7	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	00			71	-	
Fall Time	t <sub>f</sub>				41	-	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7	A
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	18	] ^
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °	C, I <sub>S</sub> = 4 A, V <sub>GS</sub> = 0 V	-	-	1.4	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 4 A, dI/dt = 100 A/µs, V <sub>R</sub> = 400 V		-	192	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			_	2.4	-	μC
Reverse Recovery Current	I <sub>RRM</sub>				11	_	A

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

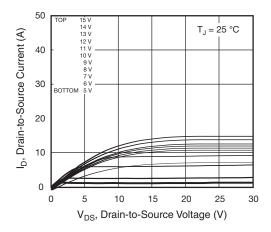


Fig. 1 - Typical Output Characteristics

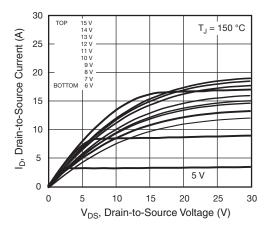


Fig. 2 - Typical Output Characteristics

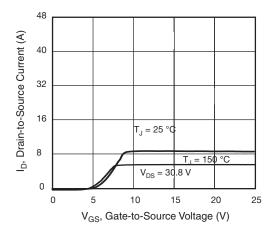


Fig. 3 - Typical Transfer Characteristics

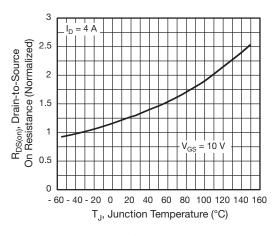


Fig. 4 - Normalized On-Resistance vs. Temperature

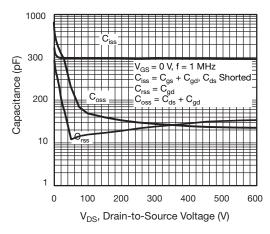


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

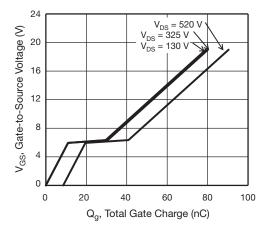


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



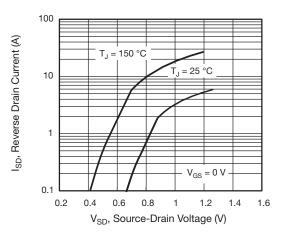


Fig. 7 - Typical Source-Drain Diode Forward Voltage

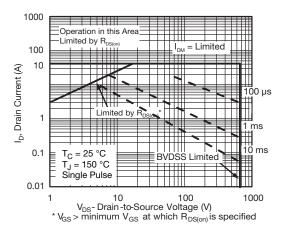


Fig. 8 - Maximum Safe Operating Area

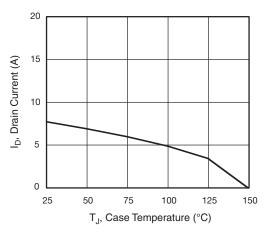


Fig. 9 - Maximum Drain Current vs. Case Temperature

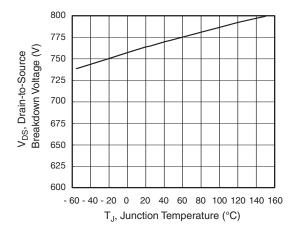


Fig. 10 - Temperature vs. Drain-to-Source Voltage

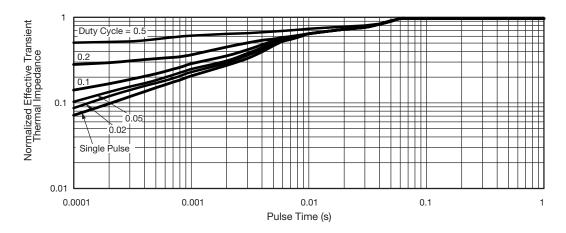


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



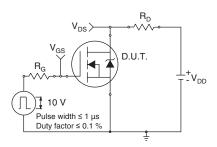


Fig. 12 - Switching Time Test Circuit

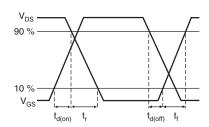


Fig. 13 - Switching Time Waveforms

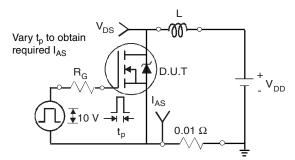


Fig. 14 - Unclamped Inductive Test Circuit

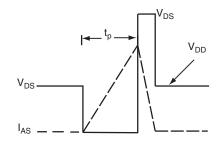


Fig. 15 - Unclamped Inductive Waveforms

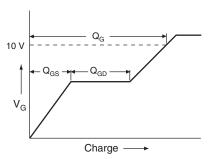


Fig. 16 - Basic Gate Charge Waveform

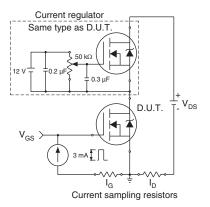
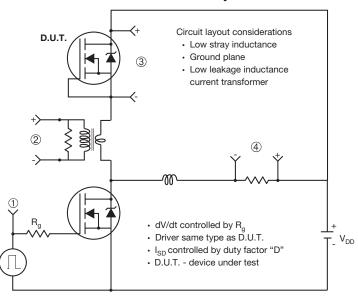


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



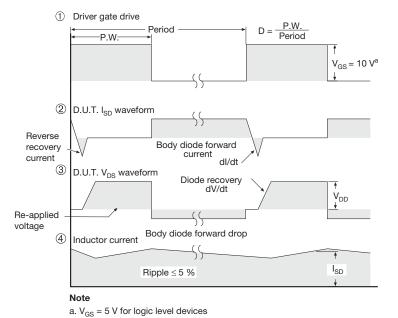
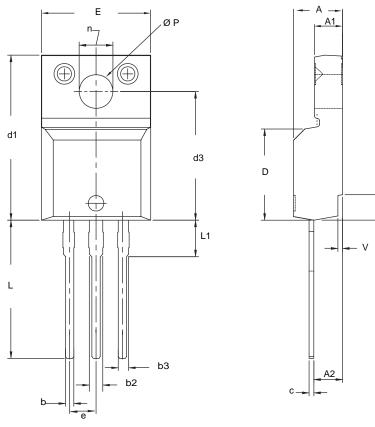


Fig. 18 - For N-Channel



### **TO-220 FULLPAK (HIGH VOLTAGE)**



DIM.	MILLIN	METERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	
Α	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
С	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408	0.419	
е	2.54	BSC	0.100 BSC		
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	0.242	
ØΡ	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

- To be used only for process drawing.
  These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
  All critical dimensions should C meet C<sub>pk</sub> > 1.33.
  All dimensions include burrs and plating thickness.
  No chipping or package damage.



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